

參考資料：

- [1] F. K. LeGoues, R. Rpsenberg, T. Nguyen, F. Himp sel, and B. S. Meyerson, J. Appl. Phys. 65(4), (1989)
- [2] F. K. LeGoues, R. Rpsenberg, and B. S. Meyerson, Appl. Phys. Lett. 54(7), (1989)
- [3] F. K. LeGoues, R. Rpsenberg, and B. S. Meyerson, Appl. Phys. Lett. 54(8), (1989)
- [4] L. Patthey, E.L. Bullock, T. Abukawa, S. Kono, L.S.O. Johansson, Phy. Rev. Lett. 75, 2538, (1995)
- [5] R. Larciprete, P. De Padova, C. Quaresima, C. Ottaviani, P. Perfetti, M. Peloi, Phy. Rev. B 61, 16006, (2000)
- [6] G. Hollinger, Applications of Surface Science, 8, 318-336, (1981).
- [7] Hollinger G. and Himp sel F.J., Phys. Rev. B, 28, 3651, (1983).
- [8] P. L. J. Gunter, A.M. de Jong and J.W. Niman tsverdriet, Surface and Interface Analysis, Vol. 19, 161-164, (1992)
- [9] Piero Pianetta, X-Ray Data Booklet Section 3.2 Low-Energy Electron Ranges in Matter.
- [10] S. Tanuma, C. J. Powell, and D. R. Penn, “Calculations of Electron Inelastic Mean Free Paths. II. Data for 27 Elements over the 50–2000 eV Range,” Surf. Interface Anal. 17. 911 (1991).
- [11] 陳貞梅，國立交通大學碩士論文，(2003).
- [12] D.-S. Lin, J.-L. Wu, S.-Y. Pan, and T.-C. Chiang, Phy. Rev. B90, 046102-1, (2003).
- [13] 潘祥元，國立交通大學碩士論文，(2001).